

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10697108	BEISEL ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Lee, Siu M	2611

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
375	224, 316	2/17/2007	Siu M. Lee
398	1-8	2/17/2007	Siu M. Lee
370	217-229	2/17/2007	Siu M. Lee

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST	2/17/2007	Siu M. Lee
Discuss the application with Cheih Fan	2/17/2007	Siu M. Lee
Discuss the amendment with Chieh Fan	8/21/2007	Siu M. Lee
EAST	8/22/2007	Siu M. Lee
EAST	3/26/2008	Siu M. Lee
Discuss the application with Chieh Fan	3/26/2008	Siu M. Lee
EAST	10/22/2008	Siu M. Lee
Discuss the amendment with Chieh Fan	10/22/2008	Siu M. Lee

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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